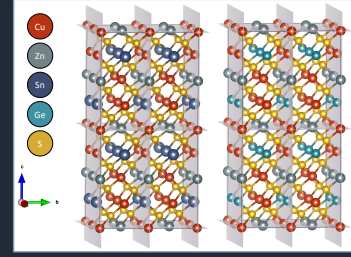




Ratz, Thomas et al. "Relevance of Ge incorporation to control the physical behaviour of point defects in kesterite" *Journal of materials chemistry A* (2022)

Motivations

- Strengthen our knowledge of CZTS and CZGS [1]
- Study the behaviour of point defects in Sn-based, Ge-doped and Ge-doped kesterites [2]
- Understand the physical origin of the V_{OC} improvement reported upon Ge incorporation
- Link defects and kesterite material properties focusing on PV applications



Identification of dominant point defects

- Pure phase limitations due to the multiple secondary phases
- Most abundant defects: Cu_{Zn} , Zn_{Cu} , V_{Cu} and X_{Zn} ($X=Sn, Ge$)
- Cu_{Zn} , Zn_{Cu} highlight the Cu/Zn disorder
- Pinning of the Fermi level led by carrier producing defects: Cu_{Zn} , Zn_{Cu} and V_{Cu}
- Upon Ge incorporation:

$$\Delta H_F(X_{Zn}) \quad (X=Sn, Ge)$$

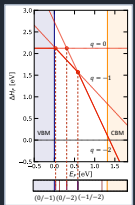
Low $\Delta H_F(Ge_{Sn})$

Theoretical approach

Thermodynamic conditions

- $\mu_i < 0$
- $\Delta H_F(Cu_{Zn}X_{Sn}) = 2\mu_{Cu} + \mu_{Zn} + \mu_X + 4\mu_S$
- $\sum_i n_i \mu_i < \Delta H_F(X_i, n_i)$

Defect formation energy $\rightarrow \Delta H_F(\alpha, q, E_F, \mu_i) =$



$$E(\alpha, q) - E_{host}$$

Total energy difference

$$- \sum_i n_i (E_i + \mu_i)$$

Exchange of atoms

$$+ q[E_{VBM} + E_F]$$

Exchange of charges

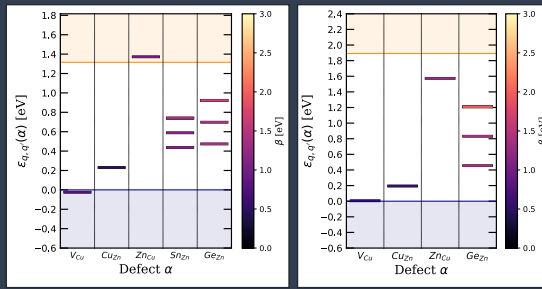
Methodology

- SCAN ionic relaxation (1E-3 eV/Å)
- One-shot HSE06 relaxation (1E-3 eV)
- 64-atoms supercell approach
- 520 eV cut-off energy, 2x2x2 k-points grid

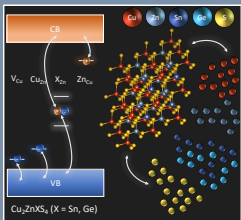
Ionisation levels of dominant point defects

- Cu_{Zn}^{-1} and V_{Cu}^{-1} providing holes
 - Zn_{Cu}^{+1} providing electrons
 - X_{Zn} provide 3 transition levels and act as a recombination centre
- p-type electrical conductivity of CZTS and CZGS

$$\varepsilon_{q,q'} = \frac{\Delta H_F(\alpha, q) - \Delta H_F(\alpha, q')}{q' - q}$$



"Bring home" message



- From [1], increase of V_{OC} and decrease of J_{SC} when Sn is substituted by Ge (perfect crystal)
- $\Delta H_F(X_{Zn})$ increases when Sn \rightarrow Ge
- Net decrease of the Ge_{Zn} lattice distortion with respect to Sn_{Zn} \rightarrow capture cross-section reduction
- Link to the Sn multivalence and so-called lone-pair effect [2]

References

[1] Ratz, Thomas, et al. "Opto-electronic properties and solar cell efficiency modelling of Cu₂ZnSnS₄ (X= Sn, Ge, Si) kesterites." *Journal of Physics: Energy* (2021), 3, 035005.
 [2] Wexler, Robert B., et al. "Optimizing kesterite solar cells from Cu₂ZnSnS₄ to Cu₂CdGe(S, Se)₄." *Journal of Materials Chemistry A* 9.15 (2021): 9882-9897.
 [3] Ji, Jieqiang, et al. "Effective and non-effective recombination center defects in Cu₂ZnSnS₄: Significant difference in carrier capture cross sections." *Chemistry of Materials* 31.3 (2019): 826-833.



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Lattice distortion associated to dominant point defects

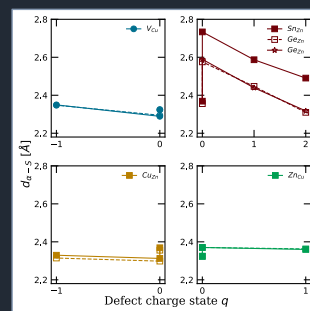
Defect emission rate:

$$e_n = \sigma_n(v) N_c \exp\left(-\frac{E_t - E_c}{k_B T}\right) \Rightarrow \text{capture cross section } \sigma_n$$

Lattice distortion upon defect incorporation

Lattice distortion

- Doping type defects lead to small lattice distortion
- Large lattice distortion reported for X_{Zn} ($X=Sn, Ge$)
- Net reduction of the lattice distortion for Ge_{Zn} with respect to Sn_{Zn} defects



Full details available \rightarrow <https://doi.org/10.1039/D1TA09620F>